

<b>Notice of References Cited</b>	Application/Control No. 10/029,727	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Tae H Yoon	Art Unit 1714	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,747,596	05-1998	Emert et al.	525/298
	C	US-6,414,069	07-2002	Pinnavaia et al.	524/445
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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